

<b>Notice of References Cited</b>	Application/Control No. 10/750,256	Applicant(s)/Patent Under Reexamination O'CONNOR ET AL.	
	Examiner James F. Sugent	Art Unit 2116	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0221185 A1	11-2004	Bose et al.	713/300
*	B	US-2005/0251621 A1	11-2005	Theis, Jean-Paul	711/118
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rotenberg, Eric, et al.; Trace Cache: a Low Latency Approach to High Bandwidth Instruction Fetching; IEEE: Published Proceeding for the 29th Annual International Symposium on Microarchitecture, Dec. 2-4, 1996; 1996
	V	IEEE 100: The Authoritative Dictionary of IEEE Standards Terms, 7 <sup>th</sup> Ed.; IEEE Press Publications; 2000; ISBN: 0-7381-2601-2
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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